

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type ( $\pi$ -MOSVI)

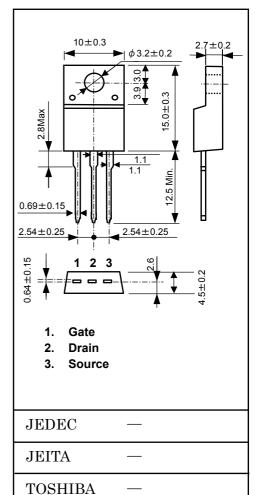
# 2SK3563

Switching Regulator Applications

- Low drain-source ON resistance:  $R_{DS}$  (ON) = 1.35  $\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 3.5S$  (typ.)
- Low leakage current:  $I_{DSS} = 100 \ \mu A (V_{DS} = 500 \text{ V})$
- Enhancement-mode:  $V_{th} = 2.0 \sim 4.0 \text{ V} (V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA})$

#### Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		V <sub>DSS</sub>	500	V
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		V <sub>DGR</sub>	500	V
Gate-source voltage		V <sub>GSS</sub>	±30	V
Drain current	DC (Note 1)	۱ <sub>D</sub>	5	
	Pulse (t = 1 ms) (Note 1)	I <sub>DP</sub>	20	A
Drain power dissipation (Tc = 25°C)		PD	35	W
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	180	mJ
Avalanche current		I <sub>AR</sub>	5	А
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	3.5	mJ
Channel temperature		T <sub>ch</sub>	150	°C
Storage temperature range		T <sub>stg</sub>	-55~150	°C



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### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	3.57	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W

Note 1: Please use devices on conditions that the channel temperature is below 150°C.

Note 2:  $V_{DD} = 90 \text{ V}, \text{ T}_{ch} = 25^{\circ}\text{C}(\text{initial}), \text{ L} = 12.2 \text{ mH}, \text{ I}_{AR} = 5 \text{ A}, \text{ R}_{G} = 25 \Omega$ 

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution.

unit : mm

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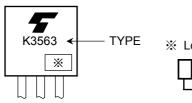
**Electrical Characteristics (Ta = 25°C)** 

Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS}=\pm 25~V,~V_{DS}=0~V$	_		±10	μA
Gate-source brea	akdown voltage	V (BR) GSS	$I_D=\pm 10~\mu A,~V_{GS}=0~V$	±30			V
Drain cut-off curr	ent	I <sub>DSS</sub>	$V_{DS} = 500 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			100	μA
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	500			V
Gate threshold ve	oltage	V <sub>th</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA}$	2.0		4.0	V
Drain-source ON	resistance	R <sub>DS (ON)</sub>	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 2.5 \text{ A}$		1.35	1.50	Ω
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 2.5 \text{ A}$	1.5	3.5		S
Input capacitance		C <sub>iss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz		550		pF
Reverse transfer capacitance		C <sub>rss</sub>			7		
Output capacitance		C <sub>oss</sub>			70		
Switching time	Rise time	tr	$ \begin{array}{c} 10 \text{ V} \\ \text{V}_{GS} \\ 0 \text{ V} \\ 15 \Omega \\ \text{W}_{GS} \\ \text{V}_{DD} \simeq 225 \text{ V} \end{array} $		10		
	Turn-on time	t <sub>on</sub>		_	20	_	
	Fall time	t <sub>f</sub>		_	10	—	ns
	Turn-off time	t <sub>off</sub>	Duty $\leq$ 1%, t <sub>w</sub> = 10 $\mu$ s	_	50		
Total gate charge		Qg		_	16	—	
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \simeq 400 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 5 \text{ A}$		10		nC
Gate-drain charge		Q <sub>gd</sub>			6	—	

## Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	—	_	_	5	А
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	—	_	_	20	А
Forward voltage (diode)	V <sub>DSF</sub>	$I_{DR} = 5 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	$I_{DR} = 5 \text{ A}, \text{ V}_{GS} = 0 \text{ V},$	—	1400	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dI <sub>DR</sub> /dt = 100 A/µs	_	9	_	μC

## Marking



※ Lot Number



Month (Starting from Alphabet A) Year (Last Number of the Christian Era)



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